

March 1996



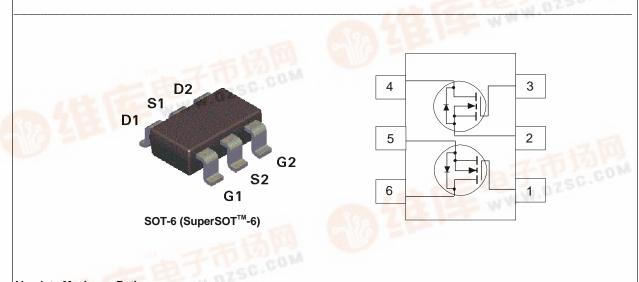
# NDC7002N Dual N-Channel Enhancement Mode Field Effect Transistor

#### **General Description**

These dual N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process has been designed to minimize on-state resistance, provide rugged and reliable performance and fast switching. These devices is particularly suited for low voltage applications requiring a low current high side switch.

## Features

- 0.51A, 50V,  $R_{DS(ON)} = 2\Omega @ V_{GS} = 10V$
- High density cell design for low R<sub>DS(ON)</sub>.
- Proprietary SuperSOT<sup>™</sup>-6 package design using copper lead frame for superior thermal and electrical capabilities.
- High saturation current.



Absolute	Maximum Ratings T <sub>A</sub> = 25°C unless otherwise	se noted		
Symbol	Parameter		NDC7002N	Units
V <sub>DSS</sub>	Drain-Source Voltage		50	V
V <sub>GSS</sub>	Gate-Source Voltage - Continuous		20	V
I <sub>D</sub>	Drain Current - Continuous	(Note 1a)	0.51	Α
	- Pulsed		1.5	
P <sub>D</sub>	Maximum Power Dissipation	(Note 1a)	0.96	W
	- 13	(Note 1b)	0.9	
	~ 7 TD 14	(Note 1c)	0.7	
T_J,T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to 150	°C
THERMA	L CHARACTERISTICS	•		
R <sub>øja</sub>	Thermal Resistance, Junction-to-Ambient	(Note 1a)	130	°C/W
R <sub>ØJC</sub>	Thermal Resistance, Junction-to-Case	(Note 1)	60	°C/W

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Symbol	Parameter	Conditions		Min	Тур	Max	Units
OFF CHA	ARACTERISTICS						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$		50			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{\rm DS} = 40 \text{ V}, V_{\rm GS} = 0 \text{ V}$				1	μA
			T <sub>J</sub> = 125°C			500	
I <sub>GSSF</sub>	Gate - Body Leakage, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
I <sub>GSSR</sub>	Gate - Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
ON CHA	RACTERISTICS (Note 2)						
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 250 \ \mu {\rm A}$		1	1.9	2.5	V
			T <sub>J</sub> = 125°C	0.8	1.5	2.2	
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 0.51 \text{ A}$			1	2	Ω
			T <sub>J</sub> = 125°C		1.7	3.5	
		$V_{GS} = 4.5 \text{ V}, \ I_{D} = 0.35 \text{ A}$			1.6	4	
I <sub>D(on)</sub>	On-State Drain Current	$V_{GS} = 10 \text{ V}, V_{DS} = 10 \text{ V}$		1.5			Α
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 0.51 \text{ A}$			400		mS
DYNAMI	C CHARACTERISTICS						
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz			20		pF
C <sub>oss</sub>	Output Capacitance				13		pF
C <sub>rss</sub>	Reverse Transfer Capacitance				5		pF
SWITCHI	NG CHARACTERISTICS (Note 2)						
t <sub>D(on)</sub>	Turn - On Delay Time	$V_{\rm DD} = 25 \text{ V}, \ \text{I}_{\rm D} = 0.25 \text{ A}, \\ V_{\rm GS} = 10 \text{ V}, \ \text{R}_{\rm GEN} = 25 \ \Omega$			6	20	nS
t <sub>r</sub>	Turn - On Rise Time				6	20	
t <sub>D(off)</sub>	Turn - Off Delay Time				11	20	
t <sub>f</sub>	Turn - Off Fall Time				5	20	
Q <sub>q</sub>	Total Gate Charge	$V_{DS} = 25 V,$ $I_{D} = 0.51 A, V_{GS} = 10 V$			1		nC
Q <sub>gs</sub>	Gate-Source Charge				0.19		nC
Q <sub>gd</sub>	Gate-Drain Charge				0.33		nC

ELECTRICAL CHARACTERISTICS (T <sub>A</sub> = 25°C unless otherwise noted)						
Symbol	Parameter	Conditions	Min	Тур	Max	Units
DRAIN-SOURCE DIODE CHARACTERISTICS						
I <sub>s</sub>	Maximum Continuous Source Current				0.51	А
I <sub>SM</sub>	Maximum Pulse Source Current (Note 2)				1.5	А
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, \text{ I}_{S} = 0.51 \text{ A} (Note 2)$		0.8	1.2	V

Notes:

1. R<sub>gut</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>gut</sub> is guaranteed by design while R<sub>got</sub> is determined by the user's board design.

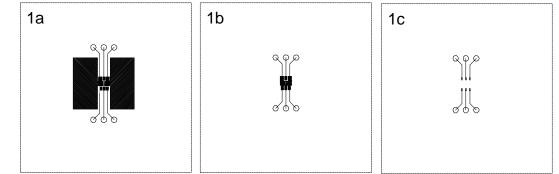
$$P_D(t) = \frac{T_J - T_A}{R_{BJ}(\delta t)} = \frac{T_J - T_A}{R_{BJ}(\delta T_B) c_A(t)} = I_D^2(t) \times R_{DS(ON)} \theta_{TJ}$$

Typical  $R_{_{BJA}}$  for single device operation using the board layouts shown below on 4.5"x5" FR-4 PCB in a still air environment:

a. 130°C/W when mounted on a 0.125 in<sup>2</sup> pad of 2oz cpper.

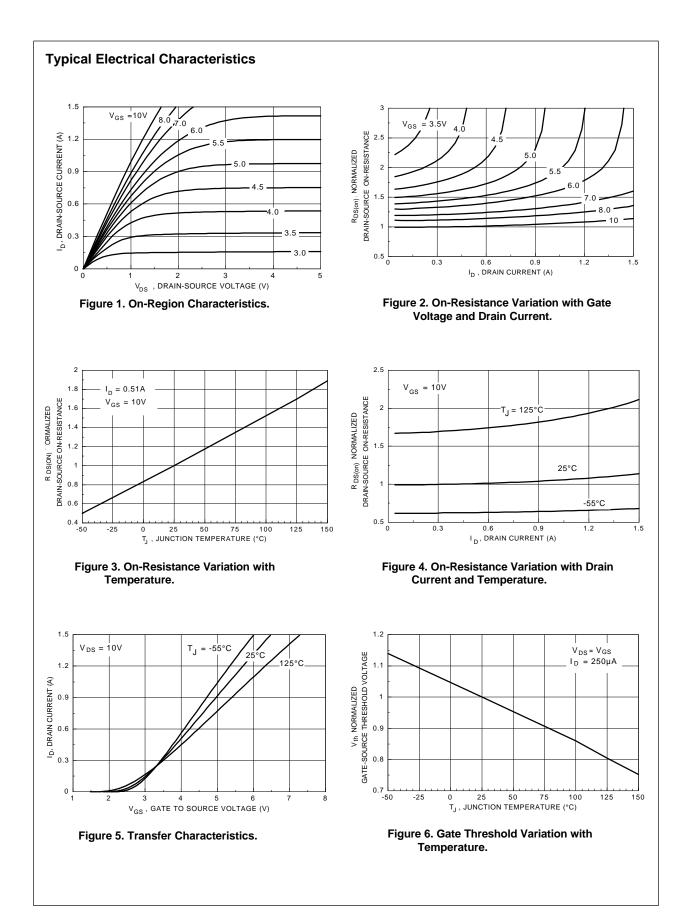
b. 140°C/W when mounted on a 0.005  $\mbox{in}^2$  pad of 2oz cpper.

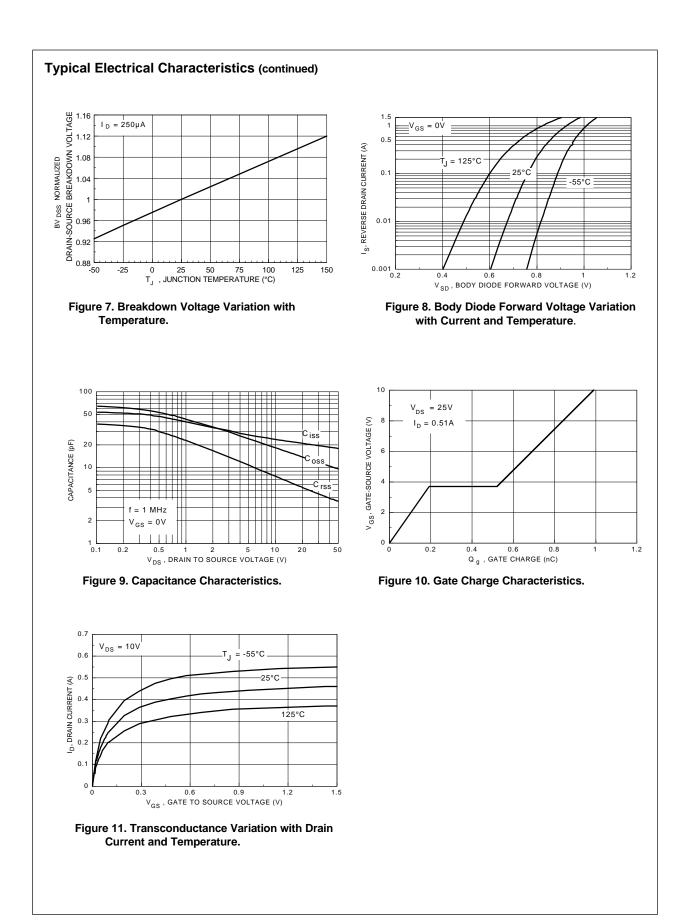
c. 180°C/W when mounted on a 0.0015  $\mbox{in}^2$  pad of 2oz cpper.

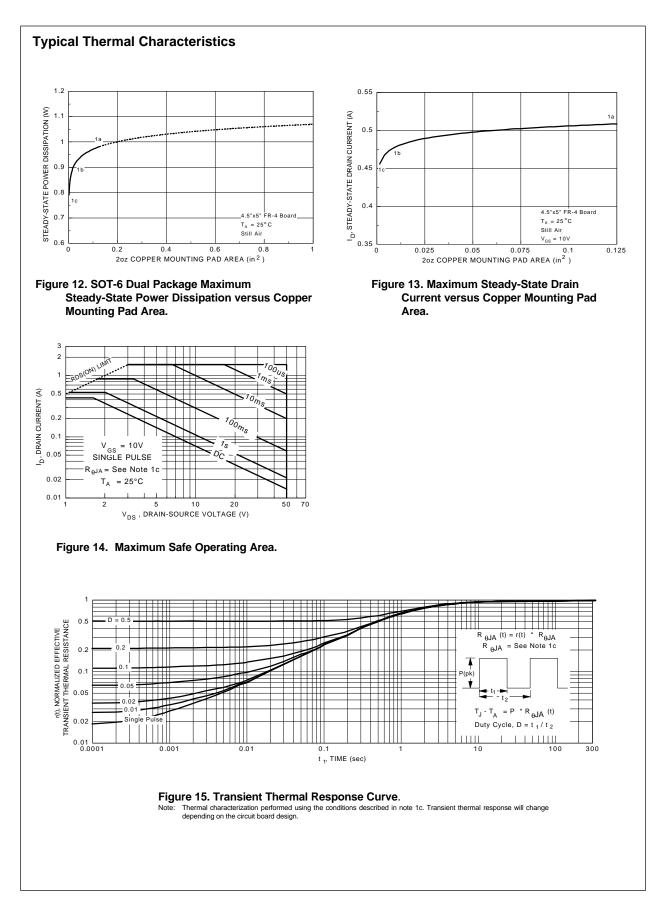


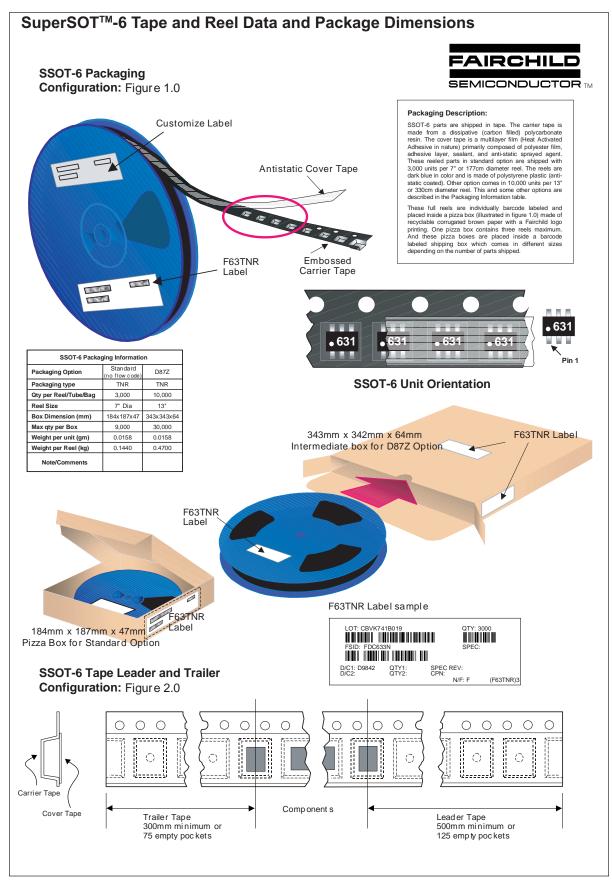
Scale 1 : 1 on letter size paper

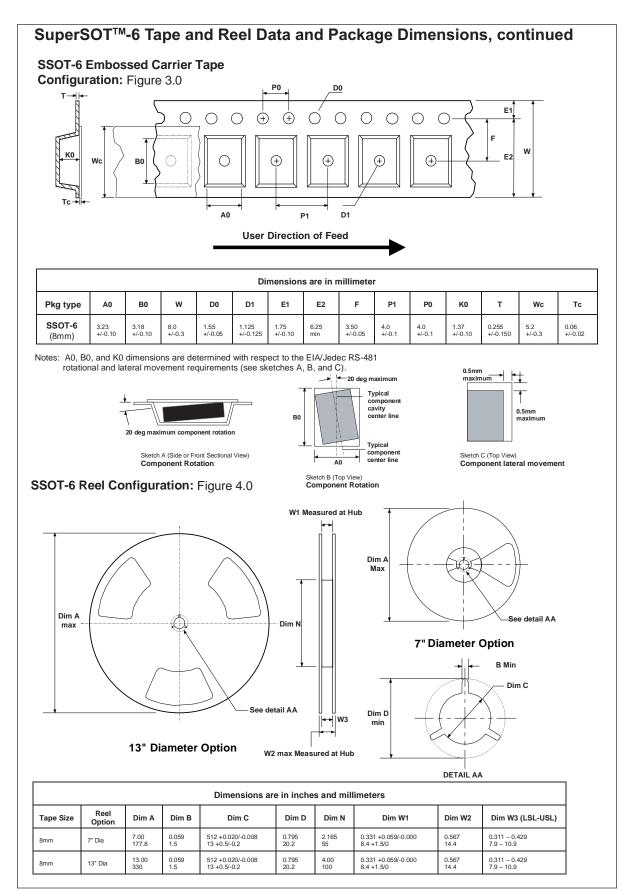
2. Pulse Test: Pulse Width  $\leq$  300µs, Duty Cycle  $\leq$  2.0%.

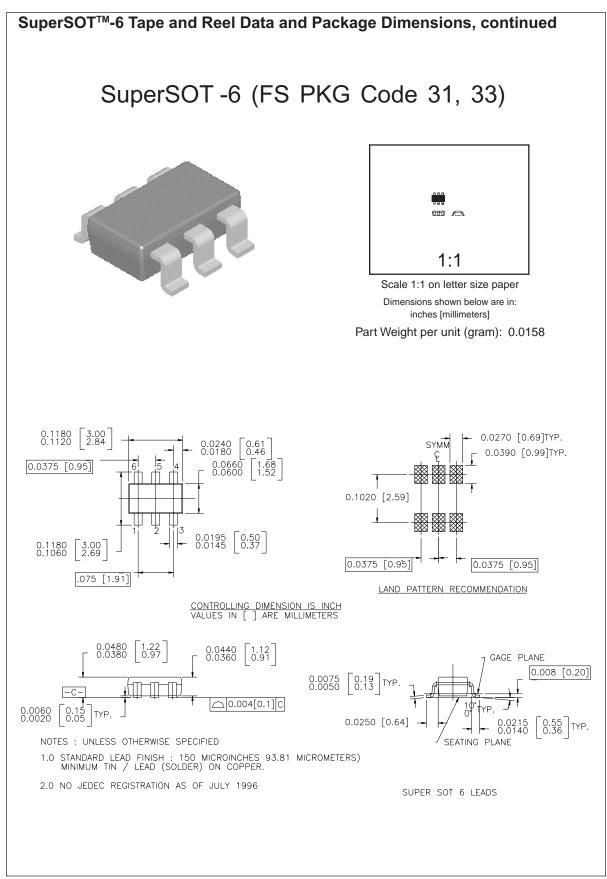












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